| PCN Number: | | | 20150929003A | | | | PCN Date: | | 12/07/ | ′2015 | | | |
|--|--|--------|--------------|----------------|-------------------------|---------|--------------------------------|--------------------|------------------------------------|-------------------------------|--------|----------------------------|-------|
| Title: | Assembly site move from Amkor K1 to Amkor P1 for Select Devices | | | | | | | | | | | | |
| Customer Contact: PCN Mar | | | | Manager | | | | | De | Dept: Quality Services | | vices | |
| Propose | d 1 st Sh | ip Da | te: | 03/07/ | ′20 | 16 | Estimated Sample Availability: | е | Date provided at sample request | | | | |
| Change | Change Type: | | | | | | | | | | | | |
| Asse | embly Sit | :e | ı | | | Desig | gn | | V | Vafer | Bumı | p Site | |
| | embly Pro | ocess | | | | Data | Sheet | | Wafer Bump Material | | | | |
| | embly Ma | | | | Part number change | | Ļ | Wafer Bump Process | | | | | |
| | hanical S | • | | | $\frac{\sqcup}{\sqcap}$ | Test | | ⊹ | Wafer Fab Site Wafer Fab Materials | | | | |
| | cing/Ship | ping/ | Labell | ng | Ш | Test | Process | ╁┾ | | | | <u>Materiai</u> Process | S |
| | | | | | | P | CN Details | | | valei | i ab i | 100033 | |
| Descript | tion of C | Chang | e: | | | | Cit Details | | | | | | |
| notification Group 2. these new Assembly | Revision A is to announce the <u>addition</u> of new devices that were not included on the original PCN notification. These new devices are highlighted in the device list below under Product Affected Group 2. The expected first shipment date for these new devices will be 90 days from this notice for these newly added devices only. Assembly site move from Amkor K1 to Amkor P1 for Select Devices listed in the "Product Affected" Section. Material differences are as follows: | | | | | | ected s notice for | | | | | | |
| Amko | | | AMI | ite Origi √ | | 7.000 | Assembly Country Code KR | | 7.00 | embly Sed | | <u> </u> | |
| Amko | r P1 | | AKI | ₹ | | | PH | Cu | pan | g, Mur | ntinlu | pa City | |
| Material Differences: Group 1 Devices: Amkor K1 Amkor P1 | | | | | | | | | | | | | |
| Mount C | Compoun | d | | 10133 | 91 | 27 | 101380679 |) | | | | | |
| Mold Co | Mold Compound 101360571 101385017 | | | | | | | | | | | | |
| Group 2 Devices: No material differences between sites. | | | | | | | | | | | | | |
| Reason for Change: | | | | | | | | | | | | | |
| Closure o | of the Am | nkor K | 1 ass | embly f | aci | lity. (| Continuity of supply. | | | | | | |
| Anticipa | ted imp | act o | n For | m, Fit, | Fu | ınctio | on, Quality or Relia | bilit | ty (| posit | ive / | ' negat | ive): |
| None. | | | | | | | | | | | | | |
| Change | to pro | duct: | donti | fication | - | ocul± | ing from this DCN: | | | | | | |

Sample Product Shipping Label (not actual product label)

Group 1: Assembly Site

| Amkor K1 | Assembly Site Origin (22L) | ASO: AMN |
|----------|----------------------------|----------|
| Amkor P1 | Assembly Site Origin (22L) | ASO: AKR |



TTEM: 39



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$12

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

ASSEMBLY SITE CODES: AMN =7, AKR = 4

Product Affected Group 1:

AFE9006RFD

Product Affected Group 2:

| 74SSTVF16859G4RG4 | ADS1258IRTCT | DDC118IRTCR | MM9635-LQ3/NOPB |
|-------------------|--------------|-----------------|-------------------|
| ADS1158IRTCR | BQ29312ARTHR | DDC118IRTCT | SN74SSTV16859RGQ8 |
| ADS1158IRTCT | DDC114IRTCR | HPA00025S8 | SN74SSTV16859RGQR |
| ADS1258IRTCR | DDC114IRTCT | MM9603-LQ4/NOPB | |

Group 1: Qualification Report Amkor K1 to P1 transfer of AFE9006RFD

Product Attributes

| Attributes | Qual Device: AFE9006RFD | | | |
|--------------------|-------------------------|--|--|--|
| Assembly Site | AP1 | | | |
| Package Family | HTFQP | | | |
| Wafer Fab Supplier | DMOS5 | | | |
| Wafer Process | 1833 CO5 | | | |

⁻ QBS: Qual By Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

| Type | Test Name / Condition | Duration | Qual Device: AFE9006RFD |
|------|-------------------------------|------------|-------------------------|
| AC | Autoclave 121C | 96 Hours | 3/231/0 |
| HAST | Biased HAST, 130C/85%RH | 96 Hours | 3/231/0 |
| HTSL | High Temp. Storage Bake, 170C | 420 Hours | 3/231/0 |
| LI | Lead Fatigue | Leads | 3/66/0 |
| LI | Lead Pull to Destruction | Leads | 3/66/0 |
| PD | Physical Dimensions | | 3/30/0 |
| TC | Temperature Cycle, -65/150C | 500 Cycles | 3/231/0 |

⁻ Qual Device AFE9006RFD is qualified at LEVEL3-260C

| WBP | Bond Pull | Wires | 3/90/0 | |
|-----|-----------------|-------|--------|--|
| WBS | Ball Bond Shear | Wires | 3/90/0 | |

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Group 2: Qualification Report QFN transfer from Amkor K1 to Amkor P1

Product Attributes

| Attributes | Qual Device: ADS1158IRTC | Qual Device: DDC118IRTCR | Qual Device: MM9603-LQ4/NOPB | Qual Device: ADC12J4000NKER / LM15851 |
|--------------------|-----------------------------|-----------------------------|---------------------------------|---|
| Assembly Site | AP1 | AP1 | AP1 | AP1 |
| Package Family | QFN | QFN | QFN | QFN |
| Wafer Fab Supplier | DMOS 5 | TSMC-WF2 | MAINEFAB | UMC12A |
| Wafer Process | 50HPA07 | 0.50UM-TSMC | C80L18M2 | UMC65NM |

- QBS: Qual By Similarity
- Qual Device ADC12J4000NKER / LM15851 is qualified at LEVEL3-260C
- Qual Device ADS1158IRTC is qualified at LEVEL2-260C
- Qual Device DDC118IRTCR is qualified at LEVEL3-260C
- Qual Device MM9603-LQ4/NOPB is qualified at LEVEL4-260C
- Device DDC118IRTCR contains multiple dies.

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

| Туре | Test Name / Condition | Duration | Qual Device: ADS1158IRTC | Qual Device: DDC118IRTCR | Qual Device: MM9603- LQ4/NOPB | Qual Device: ADC12J4000 NKER / LM15851 |
|------|----------------------------------|--------------------------|-----------------------------|-----------------------------|-------------------------------------|---|
| AC | Autoclave 121C | 96 Hours | 1/77/0 | 3/231/0 | 1/77/0 | - |
| DS | Die Shear | - | 1/10/0 | 3/90/0 | 1/10/0 | - |
| HAST | Biased HAST, 130C/85%RH | 96 Hours | - | 3/231/0 | - | - |
| HTSL | High Temp. Storage Bake, 170C | 420 Hours | - | 3/231/0 | - | 3/231/0 |
| PD | Physical Dimensions | (per mechanical drawing) | 1/5/0 | 3/15/0 | 1/5/0 | 3/15/0 |
| TC | Temperature Cycle, - 65/150C | 500 Cycles | 1/77/0 | 3/228/0 | 1/77/0 | 3/231/0 |
| WBP | Bond Pull | Wires | 1/30/0 | 3/90/0 | 1/30/0 | 3/90/0 |
| WBS | Ball Bond Shear | Bonds | 1/30/0 | 3/90/0 | 1/30/0 | 3/90/0 |
| XRAY | X-ray | (top side only) | 1/5/0 | 3/15/0 | 1/5/0 | 3/15/0 |

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

| Location | E-Mail |
|--------------|--------------------------------|
| USA | PCNAmericasContact@list.ti.com |
| Europe | PCNEuropeContact@list.ti.com |
| Asia Pacific | PCNAsiaContact@list.ti.com |
| Japan | PCNJapanContact@list.ti.com |